Modular Model-based Supervisory Controller Design for Wafer Logistics in Lithography Machines

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MODELS 2015





Embedded Systems
Innovation BY TNO



TU/e

Technische Universiteit **Eindhoven** University of Technology

Where innovation starts

Supervisory Controllers











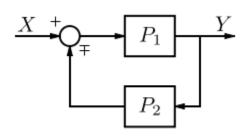






Time-driven

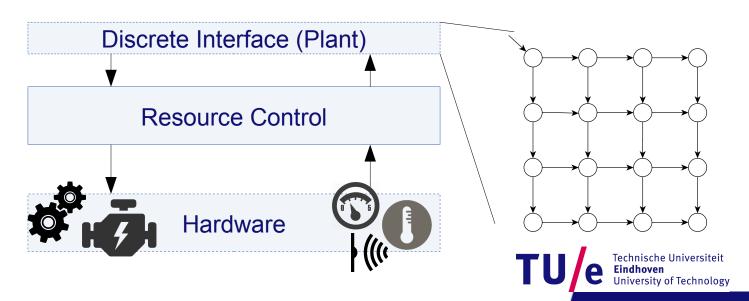


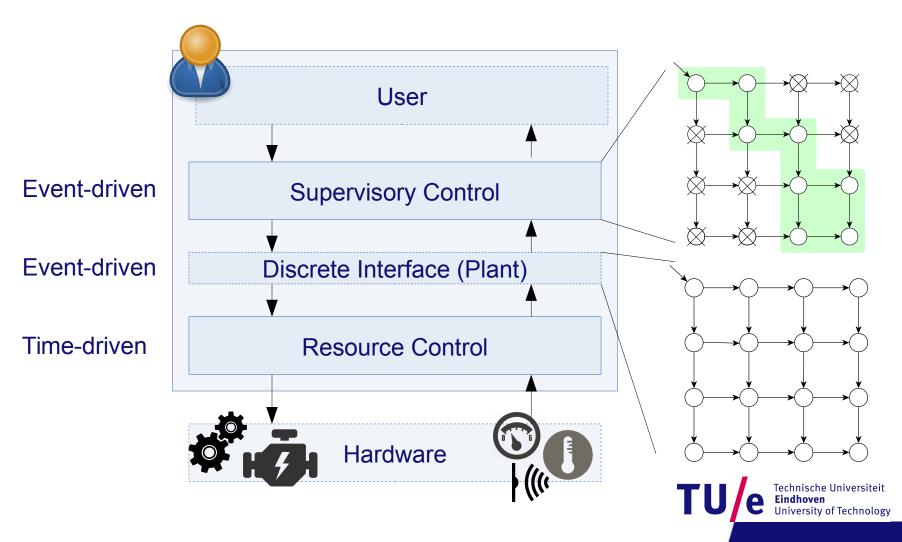




Event-driven

Time-driven





Supervisory controllers

How to design supervisory controllers?



Hybrid plant model



Discrete plant model

Hybrid plant model





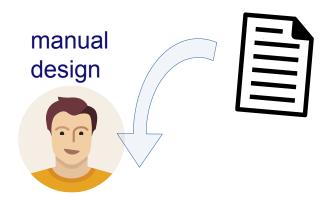


Discrete plant model

Hybrid plant model







informal requirements

supervisory controller

Discrete plant model

Hybrid plant model







informal requirements

supervisory controller

What about:

- requirement traceability?
- system is evolving: changing requirements?

Discrete plant model

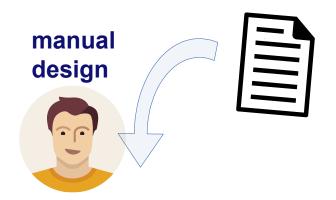
Hybrid plant model





Why not use **formally specified requirements** as part of the model?





informal requirements

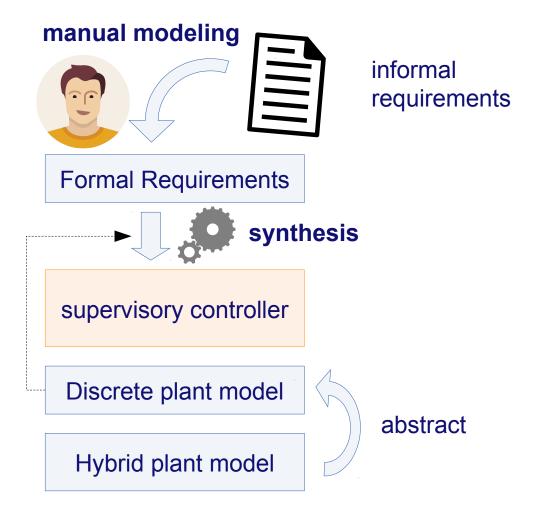
supervisory controller

Discrete plant model

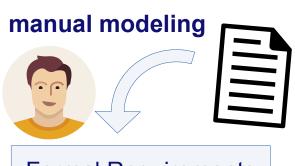
Hybrid plant model











informal requirements

Formal Requirements



supervisory controller

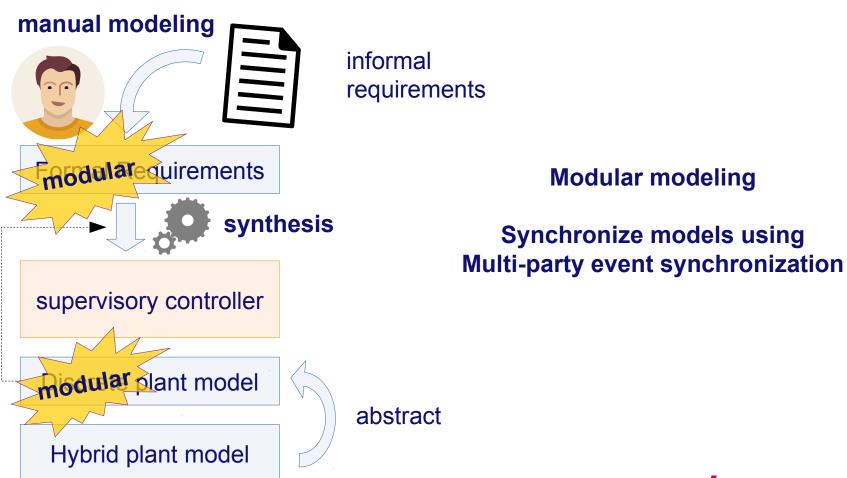
Discrete plant model

Hybrid plant model



- is deadlock-free
- is maximally permissive
- does not block environment actions

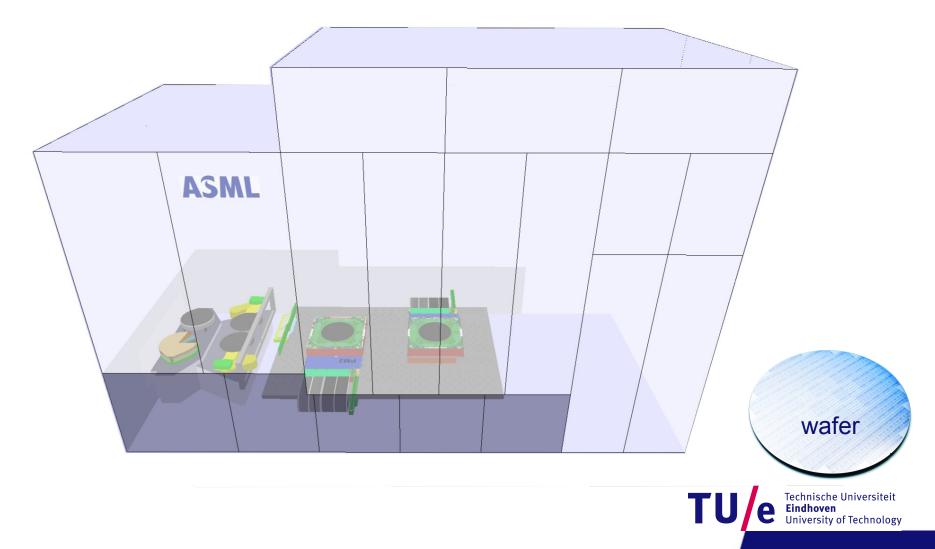


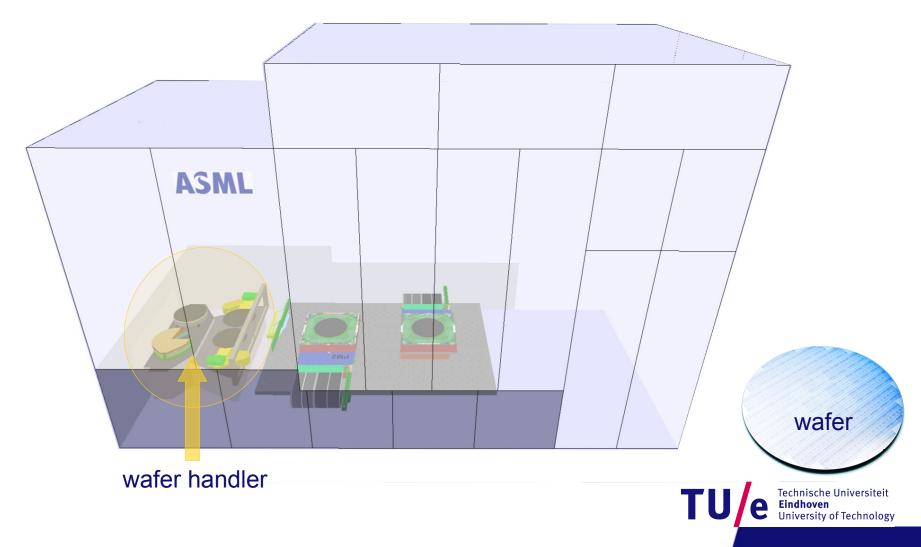


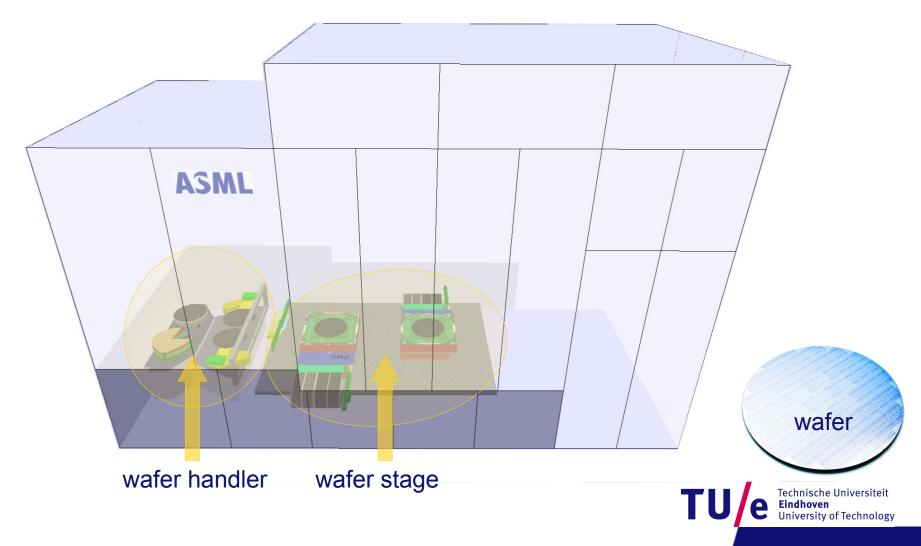
Model-based Development Process

Apply this development process to an industrial case study







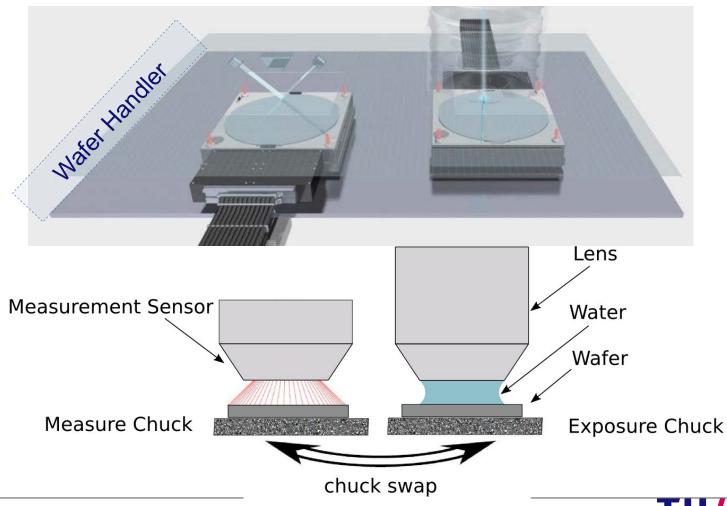


- What we have modeled in the paper:
 - Wafers
 - Positions in system
 - Life cycle requirement
 - System capabilities
 - Global flow restrictions (FIFO ordering)

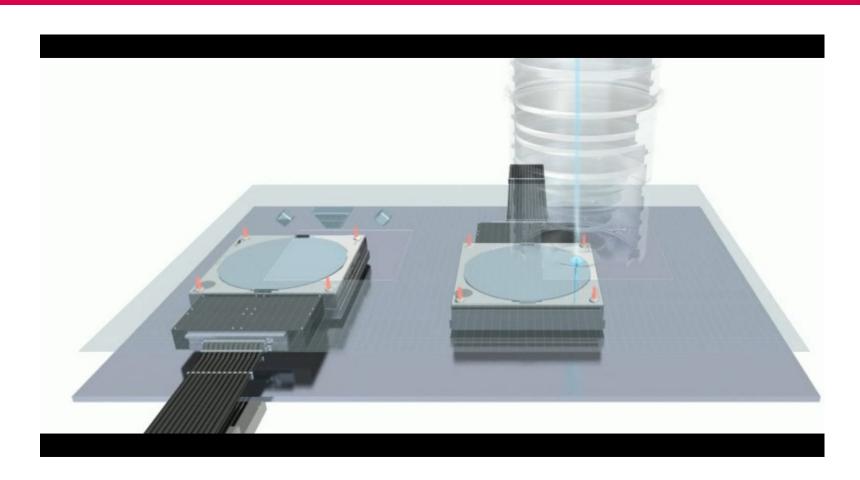
This presentation: focus on modeling the wafer stage



Wafer Stage: Measure, Expose and Chuck Swap

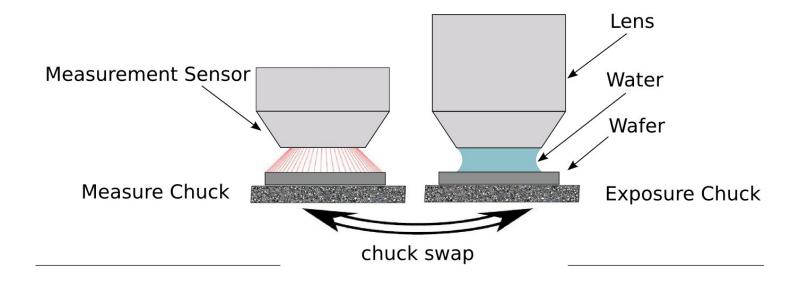


Wafer Stage: Measure, Expose and Chuck Swap





Modeling the Wafer Stage



(1) Chucks

Positions, allowed actions

Can hold at most one wafer

(2) Water layer

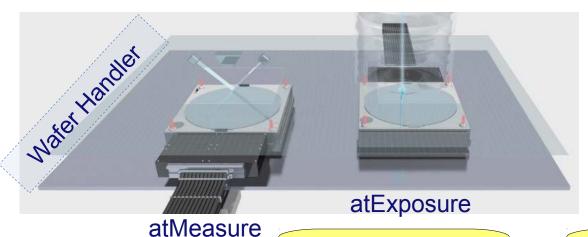
Below exposure lens

(3) Wafers

Position and life cycle

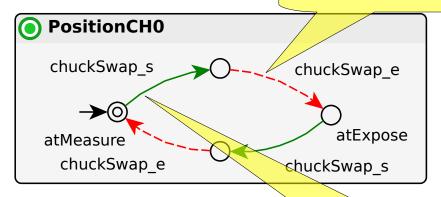


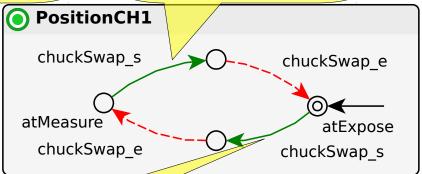
Modeling the Wafer Stage (1/3): Chuck Position



uncontrollable event

controllable event

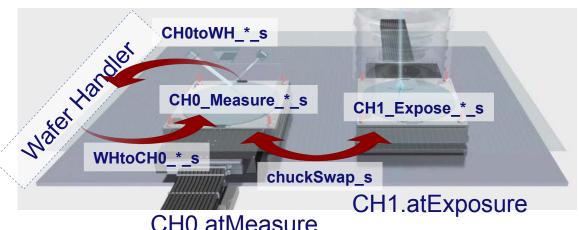




event name synchronization



Modeling the Wafer Stage (1/3): Chuck Actions



CH0.atMeasure

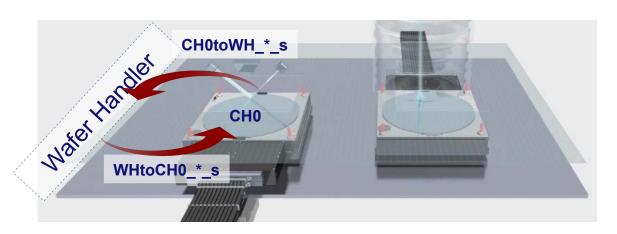
```
ActionsCH0
CHO Measure * s,
CH0toWH * s,
WHtoCH0 * s ⇒
    PositionCH0.atMeasure
CH0 Expose * s ⇒
    PositionCH0.atExpose
```

```
ActionsCH1
 CH1 Measure * s,
 CH1toWH * s,
 WHtoCH1 * s ⇒
    PositionCH1.atMeasure
 CH1 Expose * s ⇒
    PositionCH1.atExpose
```

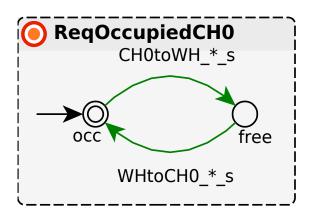
refer to states using variables

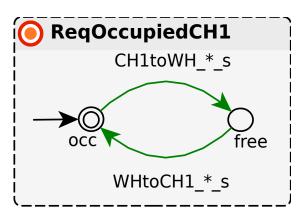


Modeling the Wafer Stage (1/3): Chuck Capacity



Chuck can hold at most one wafer

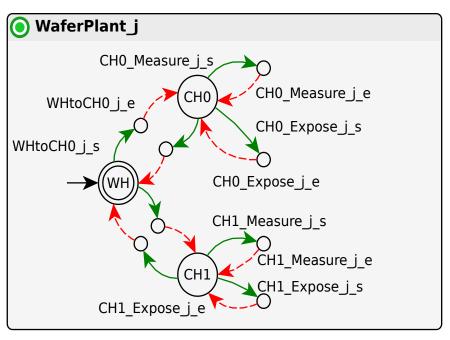




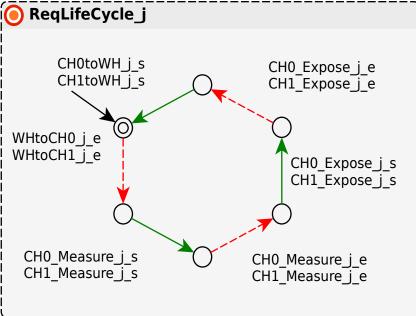


Modeling the Wafer Stage (2/3): Wafers Position and Life Cycle

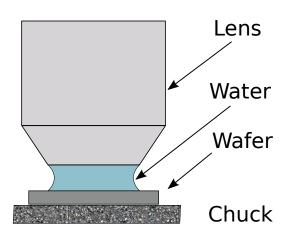
Position of wafer j

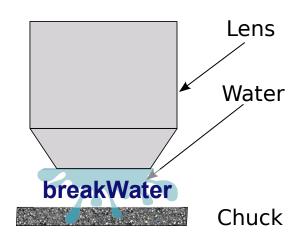


Life cycle of wafer j



Modeling the Wafer Stage (3/3): Water Layer





BreakWater

breakWater ⇒
 (PositionCH0.atExpose Λ StatusCH0.free)
v (PositionCH1.atExpose Λ StatusCH1.free)

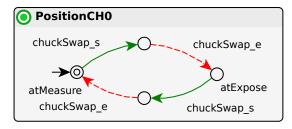
When no wafer is present below the lens, the water layer will break

ReqBreakWater
breakWater ⇒
false

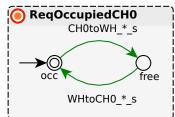
Breaking the wafer layer is never allowed



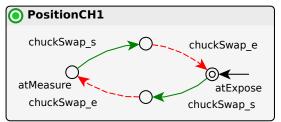
Modeling the Wafer Stage: Complete Specification Model



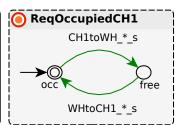
CH0_Measure_*_s, CH0toWH_*_s, WHtoCH0_*_s ⇒ PositionCH0.atMeasure CH0_Expose_*_s ⇒ PositionCH0.atExpose

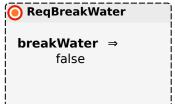


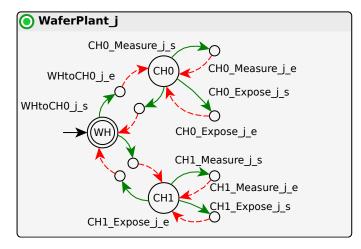


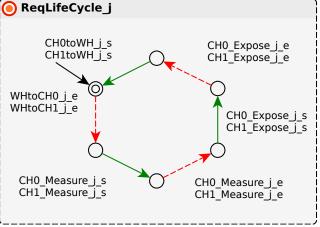




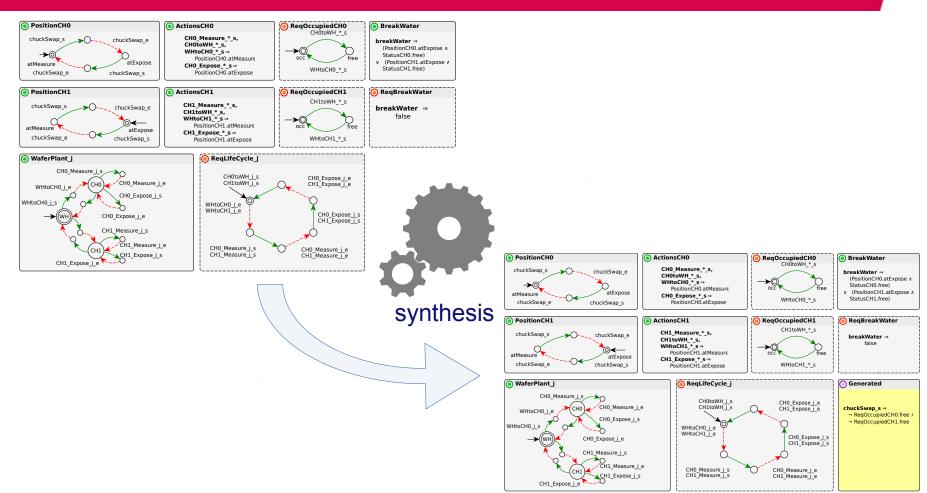




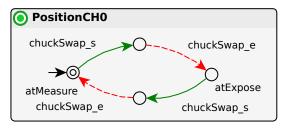


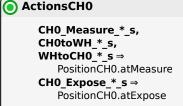


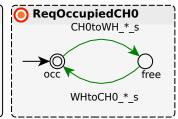
Modeling the Wafer Stage: Apply Synthesis on Specification Model



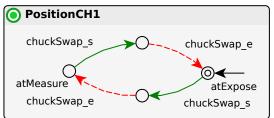
Modeling the Wafer Stage: Complete Model After Synthesis



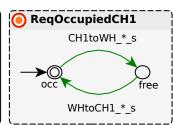


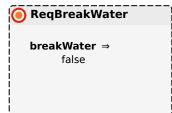


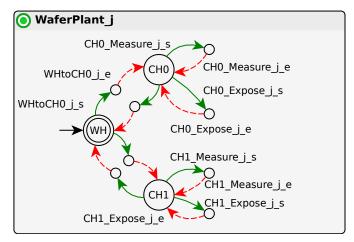


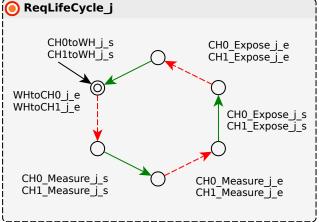


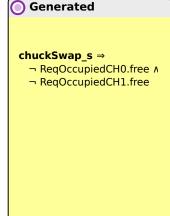












Business Case

- Why does ASML want this?
 - Controller design is now done manually:
 - Time consuming
 - Going from requirements to a supervisory controller design is difficult
 - Tight coupling between concepts: hard to make proper decomposition
 - High-tech systems evolve rapidly and adapting supervisory controllers take a lot of time
 - Exploring impact of changes is hard



Take-away points and lessons learned

- Compositional modeling of plant and requirements: divide and conquer.
- When requirements are formally part of the specification, requirement traceability is trivial.
- Multiparty synchronization provides advantages in terms of modularity and adaptability/maintainability.



Challenges: road towards industrial adaptation

- Synthesis step using monolithic synthesis does not scale well enough
 - Evaluation of modular synthesis techniques
- Completeness: specifying liveness goals, timing requirements
- Performance optimization: maximize throughput, minimize makespan



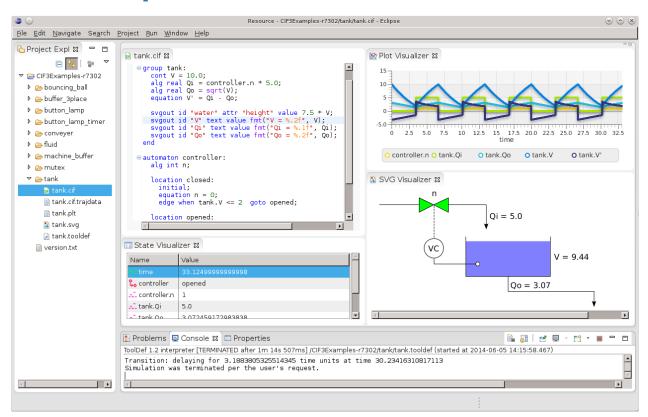
Available tooling

- CIF3: http://cif.se.wtb.tue.nl/
 - Modeling using (extended) finite (hybrid) automata
 - Synthesis of supervisors
 - (Graphical) simulation of controlled system with a discrete/hybrid plant



Available tooling: CIF3

CIF3: http://cif.se.wtb.tue.nl





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